#### **TOSHIBA Field Effect Transistor** Silicon P Channel MOS Type

# SSM5P05FU

Power Management Switch **High Speed Switching Applications** 

- Small package
- Low on resistance :  $R_{on} = 3.3 \Omega (max) (@V_{GS} = -4 V)$  $R_{on} = 4.0 \Omega (max) (@VGS = -2.5 V)$
- Low gate threshold voltage

#### Maximum Ratings (Ta = 25°C) (Q1, Q2 Common)

| Characteristics                               |       | Symbol                 | Rating  | Unit |  |
|---|-------|------------------------|---------|------|--|
| Drain-Source voltage                          |       | V <sub>DS</sub>        | -20     | V    |  |
| Gate-Source voltage                           |       | V <sub>GSS</sub>       | ±12     | V    |  |
| Drain current                                 | DC    | I <sub>D</sub>         | -200    | mA   |  |
|   | Pulse | I <sub>DP</sub>        | -400    |      |  |
| Drain power dissipation (Ta = $25^{\circ}$ C) |       | P <sub>D</sub> (Note1) | 300     | mW   |  |
| Channel temperature                           |       | T <sub>ch</sub>        | 150     | °C   |  |
| Storage temperature range                     |       | T <sub>stg</sub>       | -55~150 | °C   |  |



Weight: 6.2 mg

Note1: Total rating, mounted on FR4 board  $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu Pad: } 0.32 \text{ mm}^2 \times 5)$ 

#### **Handling Precaution**

When handling individual devices (which are not yet mounting on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

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#### Marking







### Electrical Characteristics (Ta = 25°C) (Q1, Q2 common)

| Characteristics                |               | Symbol               | Test Condition  | Min  | Тур. | Max  | Unit |  |
|--------------------------------|---------------|----------------------|---|------|------|------|------|--|
| Gate leakage current           |               | I <sub>GSS</sub>     | $V_{GS}=\pm 12~V,~V_{DS}=0$   | _    |      | ±1   | μA   |  |
| Drain-Source breakdown voltage |               | V (BR) DSS           | $I_{D} = -1 \text{ mA}, V_{GS} = 0$                                     | -20  |      |      | V    |  |
| Drain cut-off current          |               | I <sub>DSS</sub>     | $V_{DS} = -20 V, V_{GS} = 0$  |      |      | -1   | μA   |  |
| Gate threshold voltage         |               | V <sub>th</sub>      | $V_{DS} = -3 \text{ V}, \text{ I}_{D} = -0.1 \text{ mA}$                | -0.6 |      | -1.1 | V    |  |
| Forward transfer admittance    |               | Y <sub>fs</sub>      | $V_{DS} = -3 \text{ V}, \text{ I}_{D} = -50 \text{ mA}  (\text{Note2})$ | 100  |      |      | mS   |  |
| Drain-Source ON resistance     |               | R <sub>DS (ON)</sub> | $I_D = -100 \text{ mA}, V_{GS} = -4 \text{ V}$ (Note2)                  |      | 2.1  | 3.3  |      |  |
|                                |               |                      | $I_D = -50$ mA, $V_{GS} = -2.5$ V (Note2)                               |      | 3.2  | 4.0  | Ω    |  |
| Input capacitance              |               | C <sub>iss</sub>     |   |      | 27   |      | pF   |  |
| Reverse transfer capacitance   |               | C <sub>rss</sub>     | $V_{DS} = -3 V$ , $V_{GS} = 0$ , f = 1 MHz                              |      | 7    |      | pF   |  |
| Output capacitance             |               | C <sub>oss</sub>     |   |      | 21   |      | pF   |  |
| Switching time                 | Turn-on time  | t <sub>on</sub>      | $V_{DD} = -3 V$ , $I_D = -50 mA$ ,                                      | _    | 70   | —    | ns   |  |
|                                | Turn-off time | t <sub>off</sub>     | V <sub>GS</sub> = 0~-2.5 V  | _    | 70   |      |      |  |

Note2: Pulse test

#### Switching Time Test Circuit (Q1, Q2 Common)

(a) Test circuit



#### Precaution

 $V_{th}$  can be expressed as voltage between gate and source when low operating current value is  $I_D = -100 \ \mu A$  for this product. For normal switching operation,  $V_{GS}\left(_{on}\right)$  requires higher voltage than  $V_{th}$  and  $V_{GS}\left(_{off}\right)$  requires lower voltage than  $V_{th}$ . (Relationship can be established as follows:  $V_{GS}$  (off) <  $V_{th}$  <  $V_{GS}$  (on) )

Please take this into consideration for using the device. VGS recommended voltage of -2.5 V or higher to turn on this product.

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-500

-400

-200

-100

-0.5

(MA)

Drain current







 $I_D - V_{DS}$ 

-1.0

Drain-Source voltage VDS (V)

Common

Ta = 25°C

-2.3

2.1

-1.9

-2.0

VGS = -1.5 V

-1.5

Source







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#### (Q1, Q2 common)









\*: Total rating